



PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Susumu NODA et al.

Group Art Unit: 2874

Application No.: 10/537,513

Examiner: D. PETKOVSEK

Filed: June 3, 2005

Docket No.: 123457

For: TWO-DIMENSIONAL PHOTONIC CRYSTAL OPTICAL MULTIPLEXER/
DEMULITPLEXER UTILIZING BOUNDARY REFLECTION

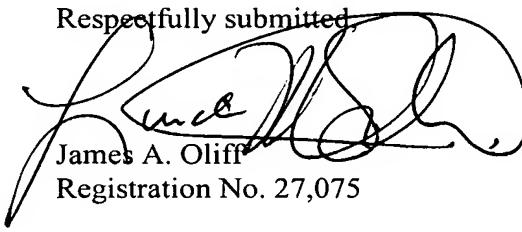
INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the reference(s) listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. The references cited herein were cited in a counterpart foreign application, but are not material to patentability of the above-identified application. Thus, it is respectfully requested that the references be placed in the application file.

Respectfully submitted,


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Date: March 8, 2007

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Sheet 1 of 1

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 123457	APPLICATION NO. 10/537,513
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)		APPLICANT(S) Susumu NODA et al.			
				FILING DATE June 3, 2005	GROUP 2874
U.S. PATENT DOCUMENTS					
Examiner Initials	Cite No.	Document Number	Date	Name	
FOREIGN PATENT DOCUMENTS					
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract With English Translation
	1	JP-A-11-218627	08/10/1999	JAPAN	
OTHER DOCUMENTS					
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)			
	2	Chutinan et al., "Surface-emitting channel drop filters using single defects in two-dimensional photonic crystal slabs," <u>Applied Physics Letters</u> , Vol. 79, No. 17, pp. 2690-2692, October 2001.			
EXAMINER				DATE CONSIDERED	
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					